

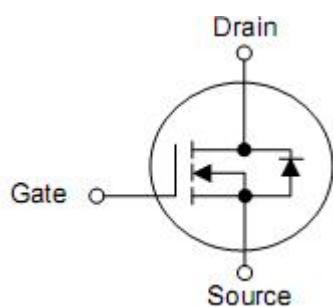
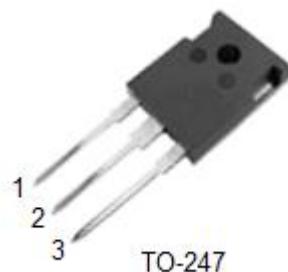
1. Features

- Fast Switching
- $R_{DS(ON)}=0.85\Omega$ (typ.)@ $V_{GS}=10V$
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

2. Applications

- DC-DC converters
- DC choppers
- AC motor control

3. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

4. Ordering Information

Part Number	Package	Brand
KNM64100A	TO-247	KIA

5. Absolute maximum ratings

$T_C=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DSS}	1000	V
Gate-to-Source Voltage	V_{GSS}	± 30	V
Continuous drain current	$T_C=25^\circ\text{C}$	I_D	A
	$T_C=100^\circ\text{C}$	I_D	A
Pulsed Drain Current at $V_{GS}=10\text{V}$ ²⁾	I_{DM}	52	A
Single pulse avalanche energy ($L=0.5\text{mH}$)	E_{AS}	1000	mJ
Peak Diode Recovery dv/dt	dv/dt	5.0	V/ns
Power dissipation	P_D	312	W
Derate above 25°C		2.5	W/ $^\circ\text{C}$
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	T_L T_{PAK}	300 260	$^\circ\text{C}$
Operating junction and storage temperature range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

6. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	$R_{\theta JC}$	0.4	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ\text{C/W}$

7. Electrical characteristics

($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	1000	-	-	V
Drain-source leakage current	I_{DSS}	$V_{\text{DS}}=1000\text{V}, V_{\text{GS}}=0\text{V}$	-	-	10	μA
		$V_{\text{DS}}=800\text{V}, T_c=125^\circ\text{C}$			250	
Gate-source forward leakage	I_{GSS}	$V_{\text{GS}}=\pm 30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Drain-source on-resistance ³⁾	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=6.5\text{A}$	-	0.85	1.15	Ω
Gate threshold voltage	$V_{\text{GS}(\text{TH})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.5	-	4.5	V
Input capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}$ $f=1\text{MHz}$	-	3865	-	pF
Reverse transfer capacitance	C_{rss}		-	104	-	pF
Output capacitance	C_{oss}		-	240	-	pF
Total gate charge	Q_g	$V_{\text{DD}}=500\text{V}, I_{\text{D}}=13\text{A}$ $V_{\text{GS}}=0\sim 10\text{V}$	-	82	-	nC
Gate-source charge	Q_{gs}		-	20	-	nC
Gate-drain charge	Q_{gd}		-	26	-	nC
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=500\text{V}, V_{\text{GS}}=10\text{V},$ $R_G=4.7\Omega, I_{\text{D}}=13\text{A}$		30		ns
Rise time	t_r			65		ns
Turn-off delay time	$t_{\text{d}(\text{off})}$			38		ns
Fall time	t_f			35		ns
Continuous Source Current ²⁾	I_{SD}	Integral PN-diode in MOSFET			13	A
Pulsed Source Current ²⁾	I_{SM}		-	-	52	
Diode forward voltage	V_{SD}	$I_{\text{S}}=13\text{A}, V_{\text{GS}}=0\text{V},$	-	-	1.5	V
Reverse Recovery Time	t_{rr}	$V_{\text{GS}}=0\text{V}, I_{\text{F}}=13\text{A},$ $dI_{\text{F}}/dt=100\text{A}/\mu\text{s}$	-	591	-	nS
Reverse Recovery Charge	Q_{rr}		-	5.4	-	μC

Note:

1) $T_J=+25^\circ\text{C}$ to $+150^\circ\text{C}$.

2) Repetitive rating; pulse width limited by maximum junction temperature.

3) Pulse width $\leq 380\text{us}$; duty cycle $\leq 2\%$.

8. Typical operating characteristics

Fig. 1 Output Characteristics

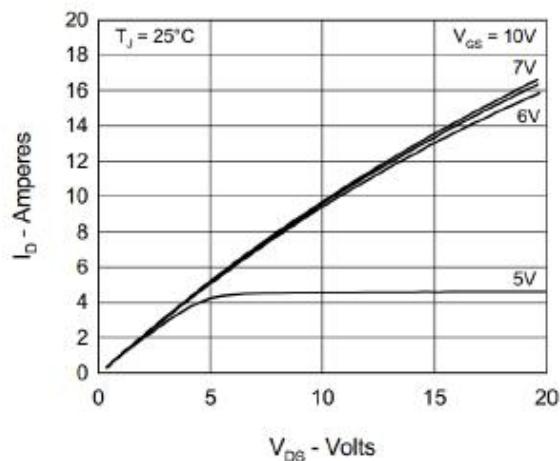


Fig. 3 $R_{DS(on)}$ vs. Drain Current

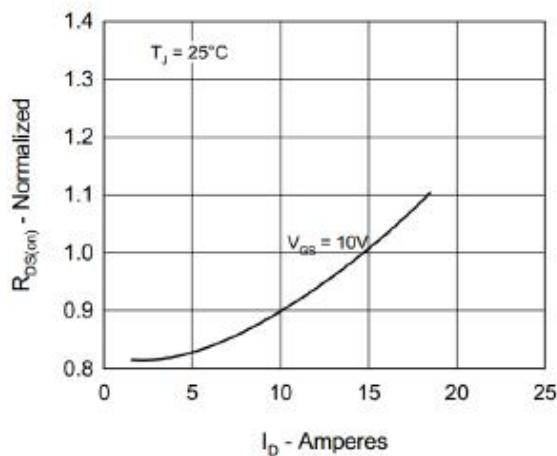


Fig. 5 Drain Current vs. Case Temperature

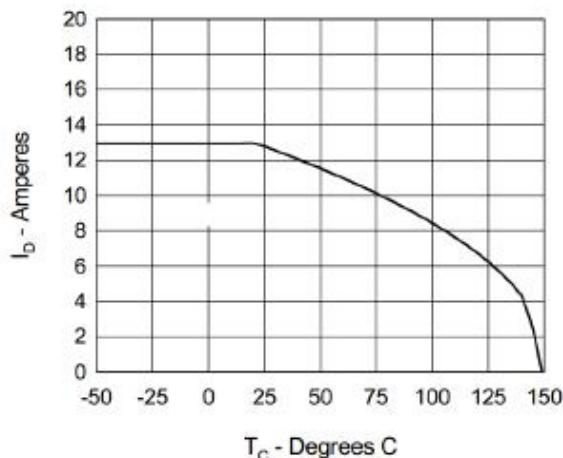


Fig. 2 Input Admittance

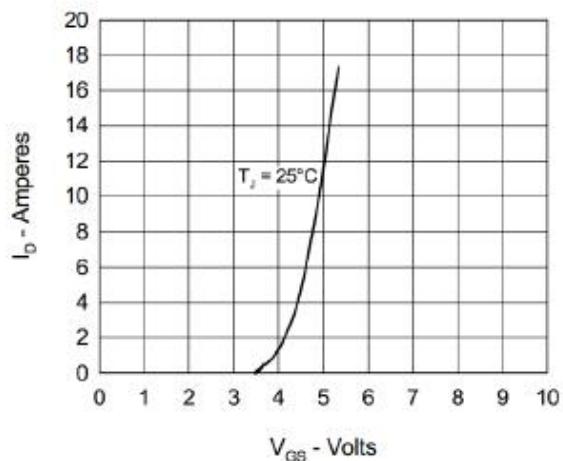


Fig. 4 Temperature Dependence of Drain to Source Resistance

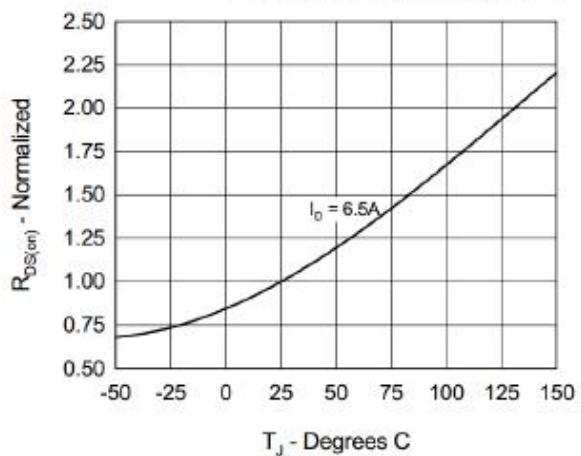


Fig. 6 Gate Charge Characteristic Curve

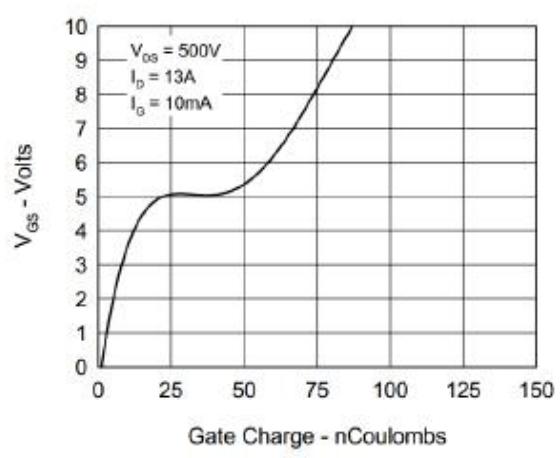


Fig.7 Capacitance Curves

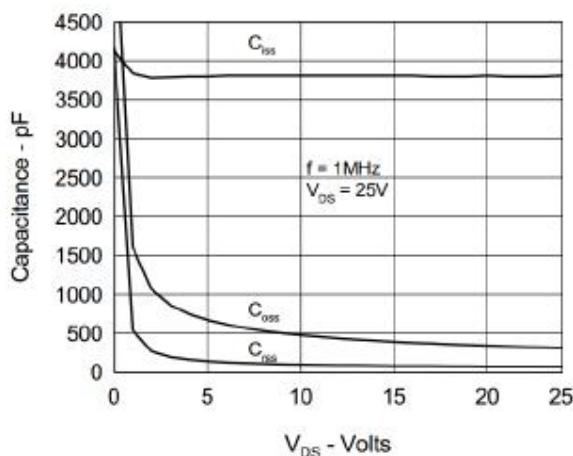


Fig.8 Source Current vs. Source to Drain Voltage

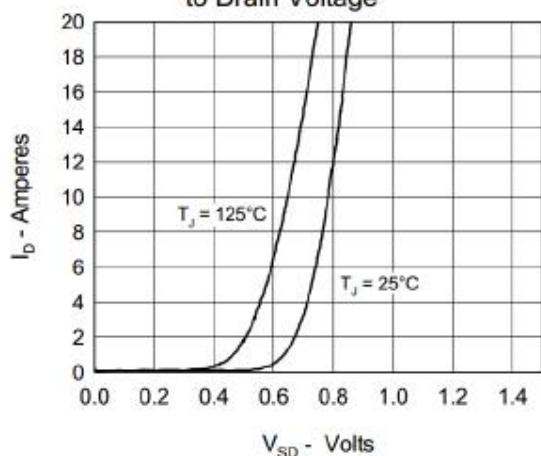
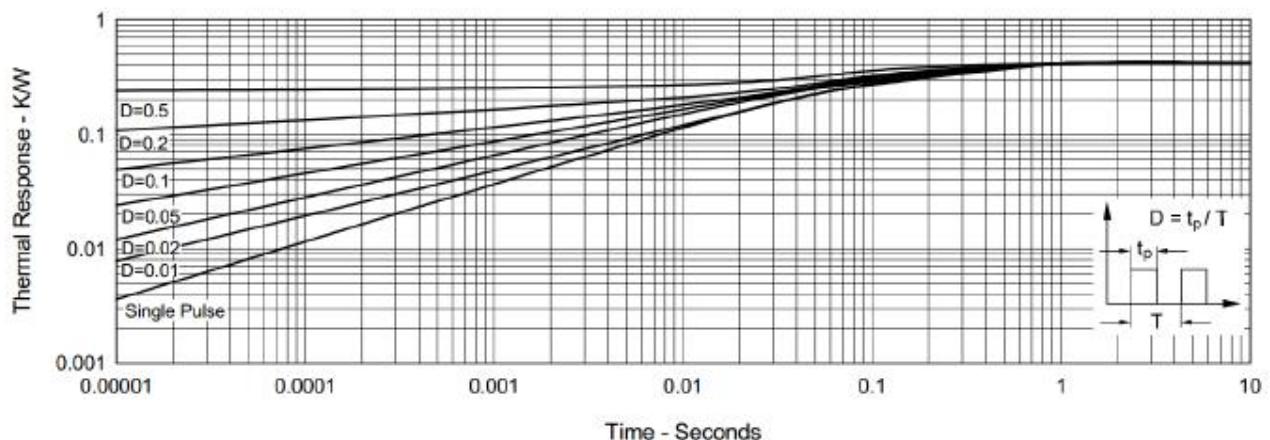


Fig.9 Transient Thermal Impedance



9. Test Circuits and Waveforms

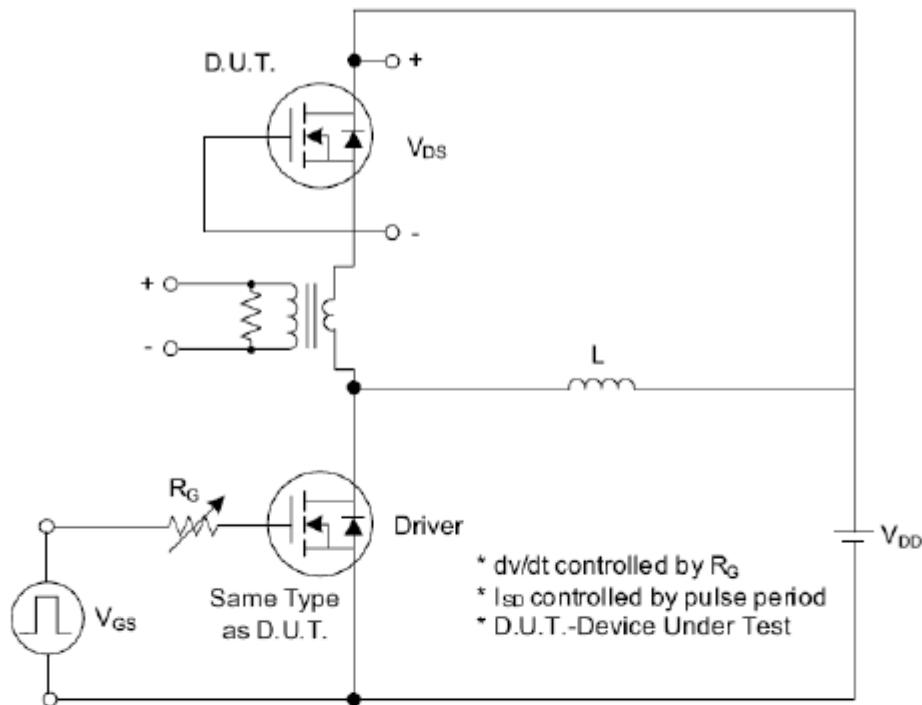


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

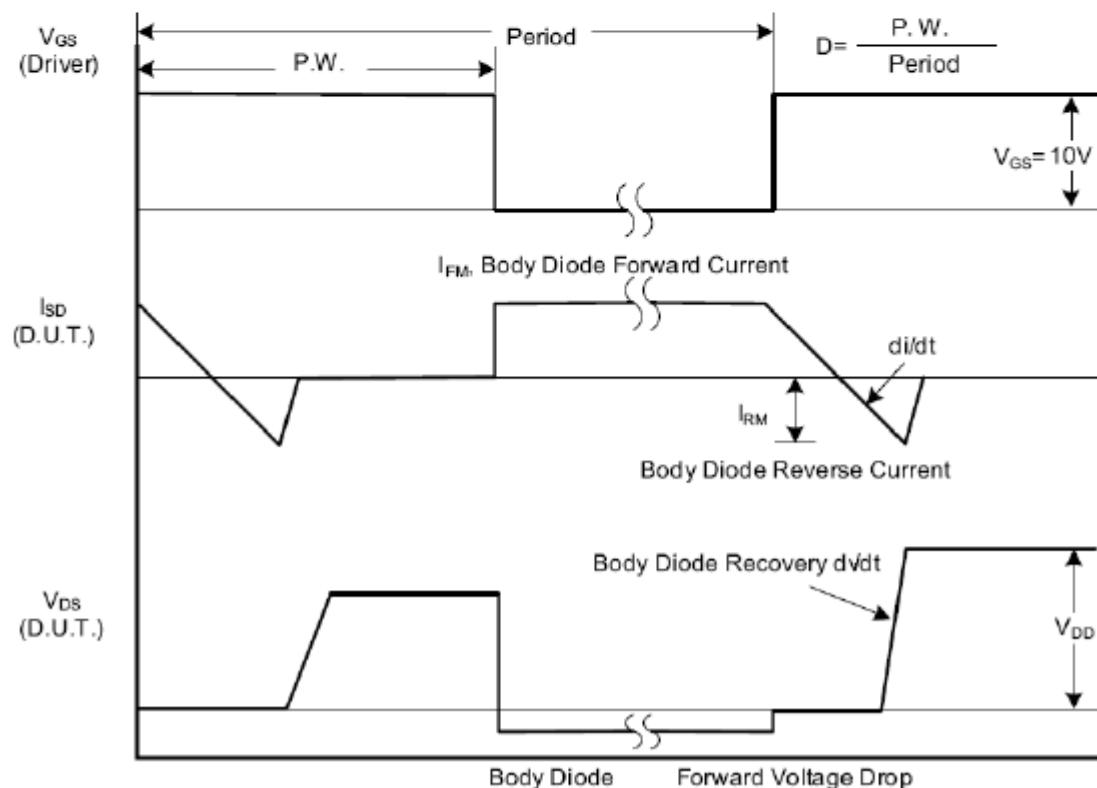


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

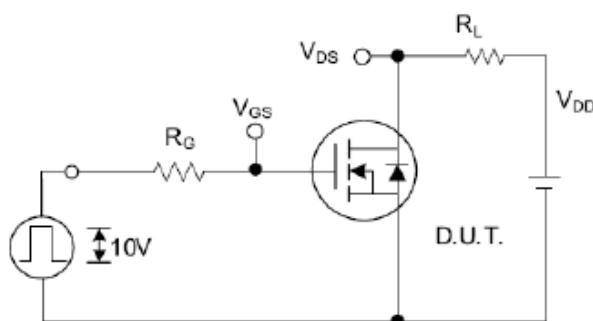


Fig. 2.1 Switching Test Circuit

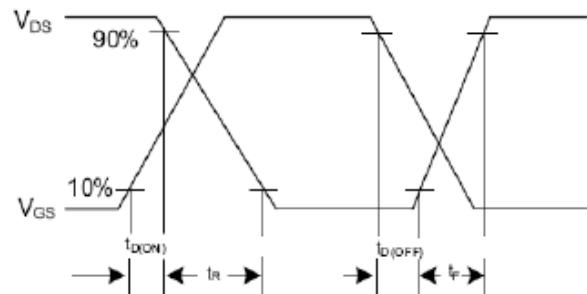


Fig. 2.2 Switching Waveforms

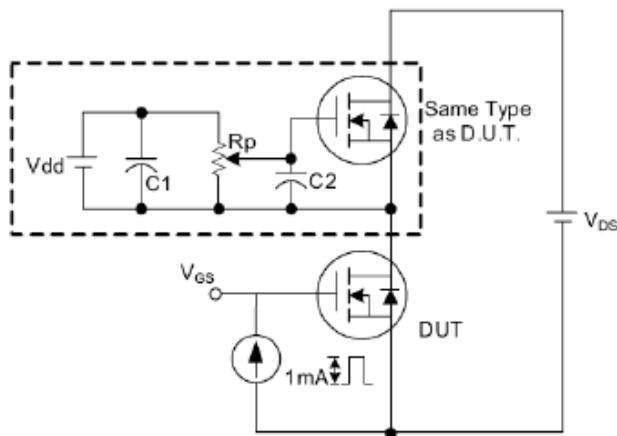


Fig. 3 . 1 Gate Charge Test Circuit

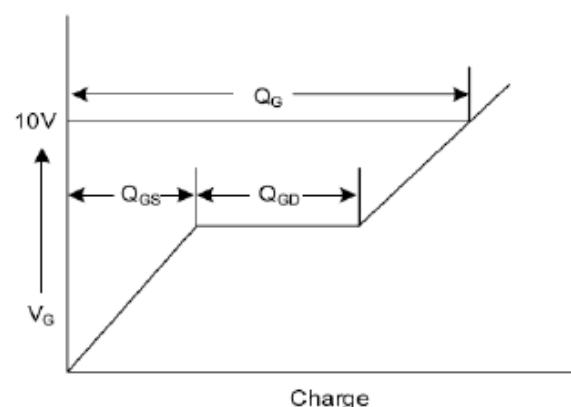


Fig. 3 . 2 Gate Charge Waveform

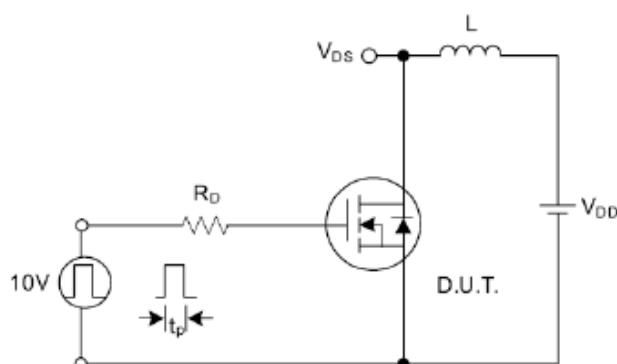


Fig. 4.1 Unclamped Inductive Switching Test Circuit

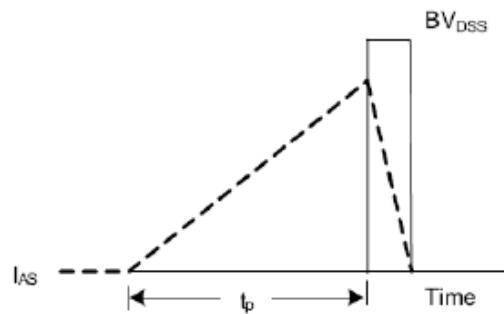


Fig. 4.2 Unclamped Inductive Switching Waveforms